

LBDS overview on system analysis and design upgrades during LS1

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CERN Workshop Machine Availability for post LS1 LHC, 28th Nov 2013

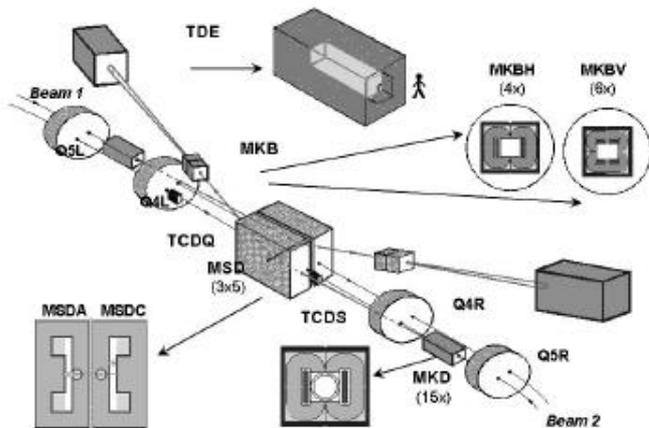
LBDS overview on system analysis and design upgrades

▶ Outline

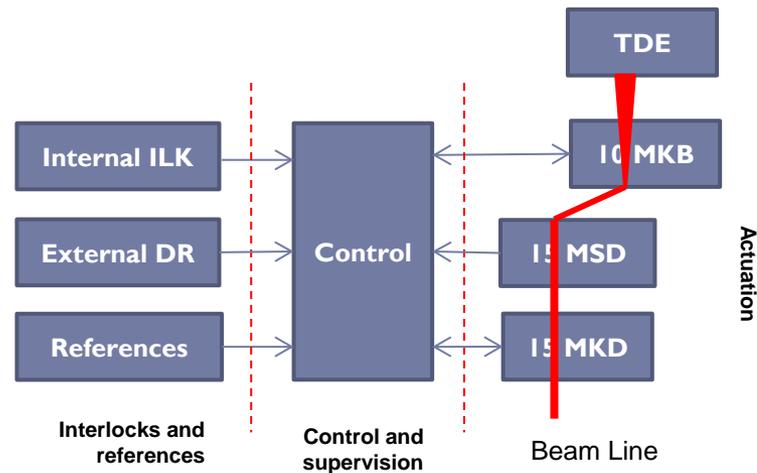
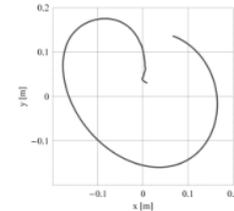
- ▶ LBDS system analysis overview
- ▶ Insights on tools and methodologies
- ▶ System changes during LS1
- ▶ Conclusions and outlook

The LHC Beam Dumping System

- ▶ The LBDS is the final element of the protection chain, it performs the extraction of the beams on demand (dump requests) either at the end of machine fills or because of safety reasons. Two LBDS exist, one per beam.



LBDS physical layout – point 6



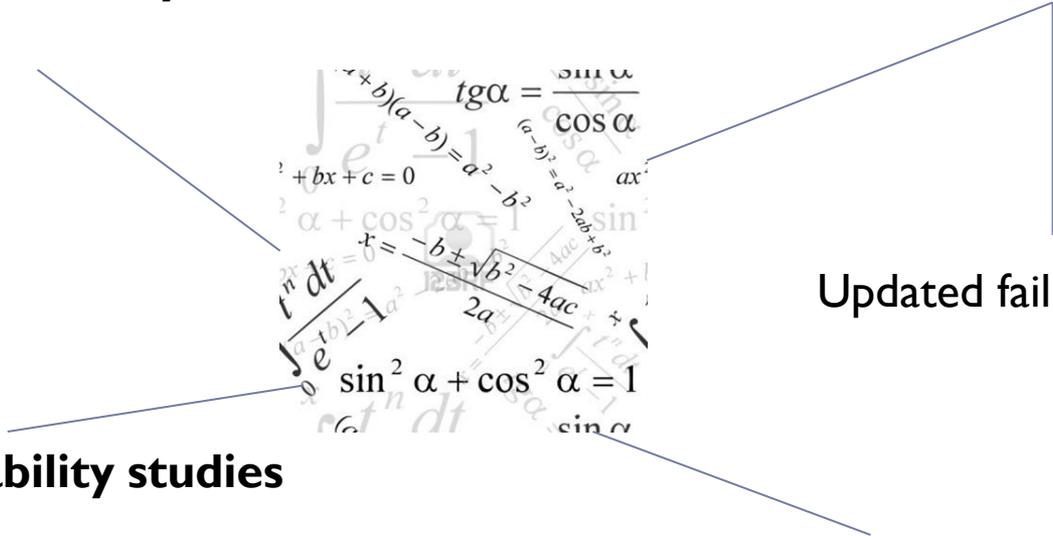
Functional layout

350 MJ destructive power

System analysis overview

Theoretical reliability models
2003-2006

Failure Statistics 2010-2012



Updated failure models

Special reliability studies
TCDQ - 2009
Triggering Synchronization and
Distribution System - 2013

Estimates of availability and safety

LBDS system analysis 2003-2006

▶ The scope

- ▶ TSDS, the beam energy tracking BETS, the septa MSD, extraction kickers MKD and dilution kickers MKB. Passive protection elements not in the scope.

▶ Assumptions

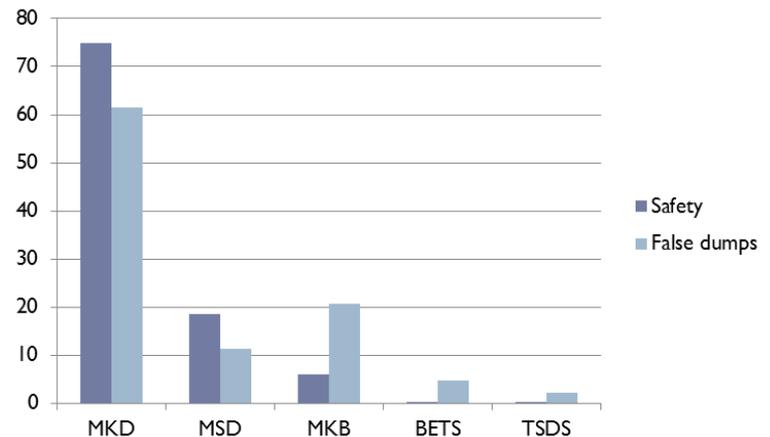
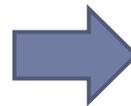
- ▶ Operation profile of 10 hours, 400 machine fills, 200 days of operation
- ▶ Post mortem diagnostics returns the system to an “as good as new” state



▶ Results

- ▶ The LBDS is **SIL 4**
- ▶ False beam dumps **8 +/- 2** per year
- ▶ Asynchronous dumps **2** per year

MKD most critical system (74%) and main cause of false beam dumps (61%)



Failure statistics 2010-2012

- ▶ **The scope**

- ▶ MKD and MKB with control and supervision electronics and diagnostics

- ▶ **Analysis of 3 years of LHC operation 2010-2012**

- ▶ Sources: LHC-OP logbook, and LHC-TE/ABT expert logbook

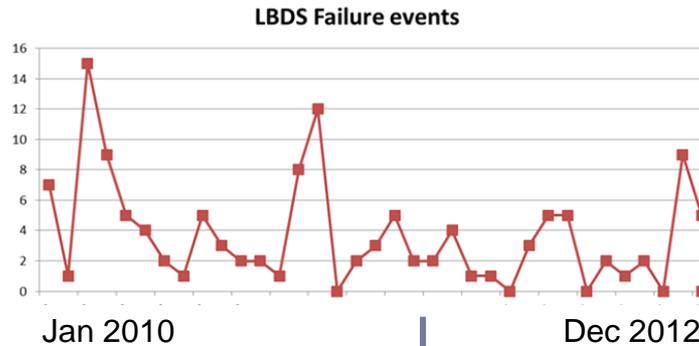


- ▶ **Results**

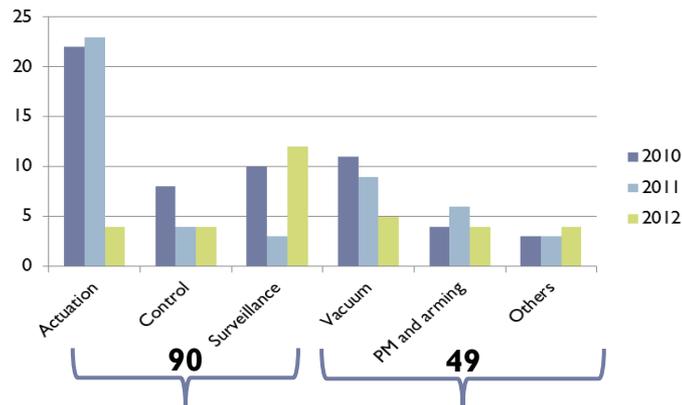
- ▶ 139 failure events of which 90 internal to LBDS
- ▶ Updated reliability prediction models
- ▶ New failure mechanisms discovered
- ▶ Availability and safety: comparison of predictions vs. statistics

Results → from raw data to statistics

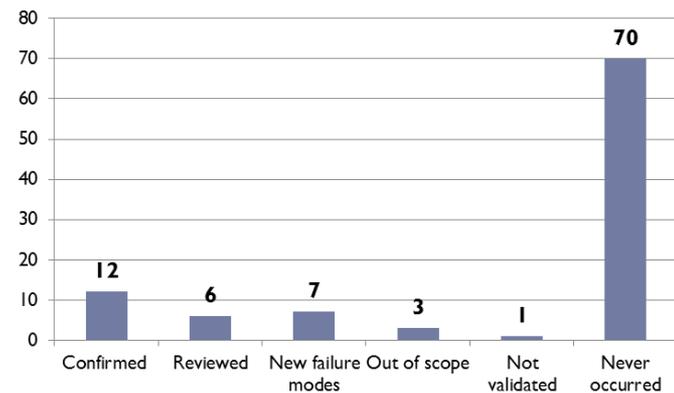
When → Raw data series
139 failure events



Where → Failure distribution
90 within the LBDS



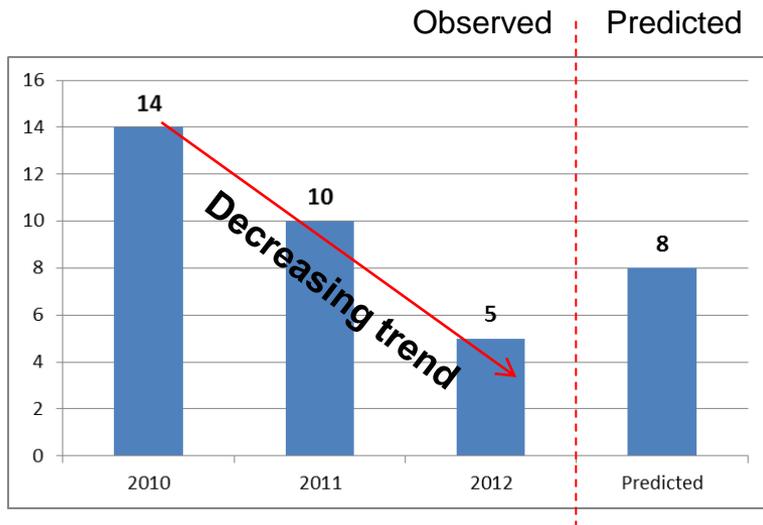
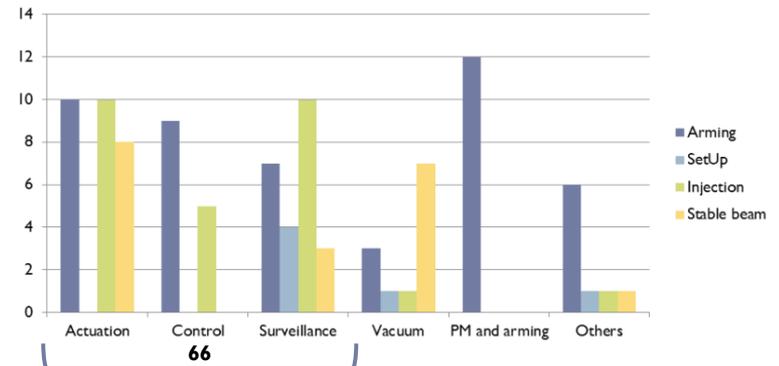
How → Failures modes observed
18 occurred over 99 identified
7 new failure modes



LBDS availability 2010-2012

- ▶ The LBDS counted **29 false beam dumps**, against 24 foreseen (8/year on average).
 - ▶ Actuation (15) then surveillance (12) and controls (2)

1- False dumps
66 apportioned to LBDS in every phase



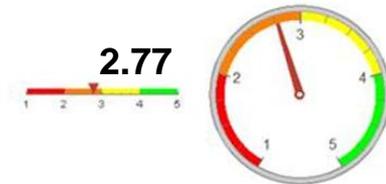
- 2 - Filtering**
- Only LBDS false beam dumps in the phases injection and stable beam
 - No repetition of the same internal dump request

LBDS safety 2010-2012

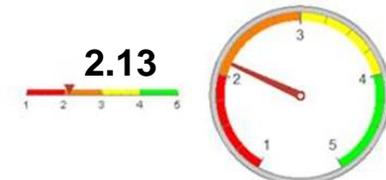
- ▶ Calculation of the safety margin at a dump request → loss of safety margins in 2011, and a recover in 2012, almost back to the initial levels of 2010
- ▶ SIL3 at least is met (hypothesis test)



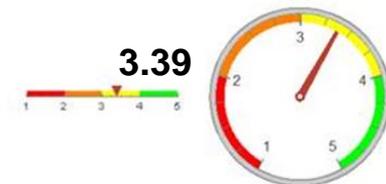
Actuation



Control



Surveillance



Remark → too much safety margin leads to an unnecessary reduction of availability

The safety gauge

Tools and Methodologies - insights

Failure statistics

Statistical framework and inference tools



Tracking availability

Safety trade-off

Availability figures

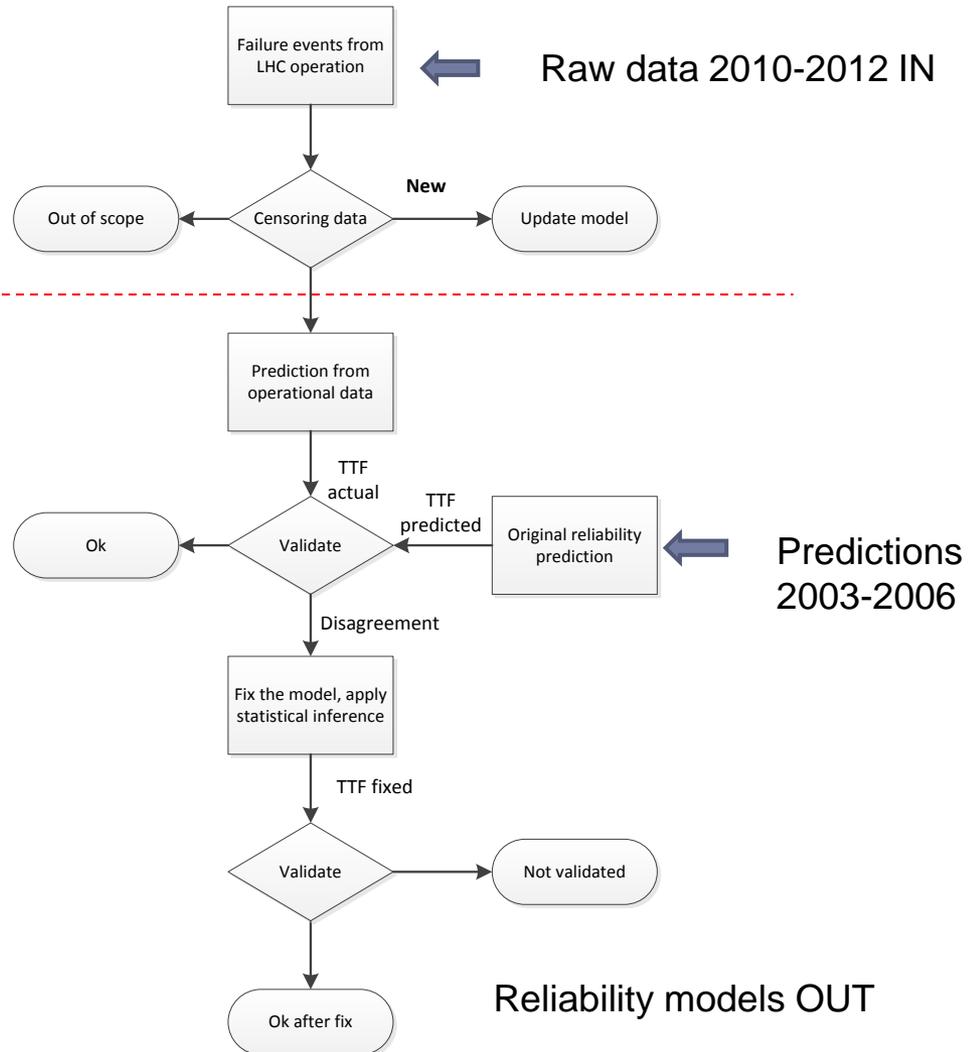
Tracking reliability

Advanced reliability prediction models

The statistical analysis framework

PHASE 1 – Censoring data

PHASE 2 – Statistics and validation



Failure modes and statistics – MKD system

The underscored figure is the one validated. Population is counted for 2 LBDS. The raw estimate refers to [Years of operations] × [population] / [number of failures]. Hypothesis test is run with $\alpha = 0.05$.

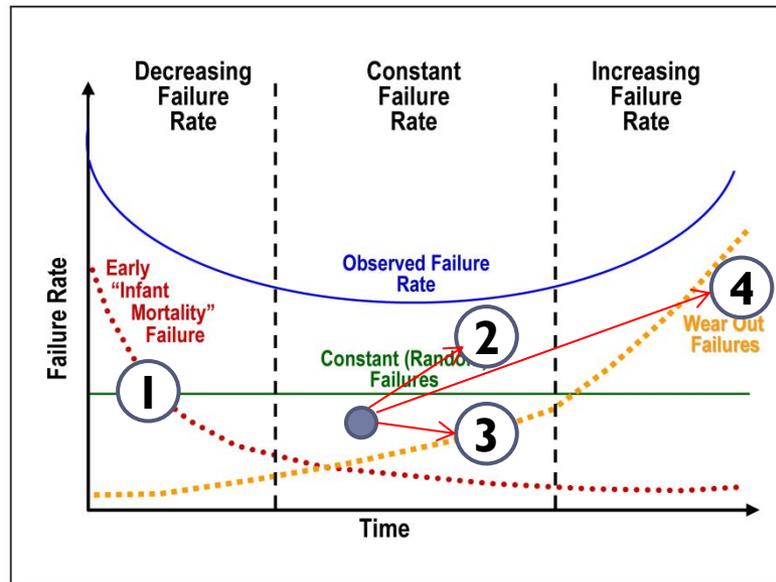
| # | Failure mode | Model | Population | Time to Failure | | | H. test | TTR (h:mm) | Time to recovery |
|----|---------------------------------|------------------|------------|-------------------------|-------------------------------|------------|-------------------|------------------|--|
| | | | | Raw | Corrected | Rel. pred. | | | |
| 1 | MKD HV power supply breakdown | PSP1 | 30 | $3 \cdot 30 / 7 = 12.8$ | β model | 150 | | 1:37 | |
| 2 | MKD PTU HV PS | HV | 60 | $3 \cdot 60 / 10 = 9$ | 1-count | <u>16</u> | TRUE | 2:18 | Validation most conservative value is kept |
| 3 | MKD Compensation PS breakdown | PSOS1 | 30 | $3 \cdot 30 / 6 = 15$ | 1-count | <u>113</u> | FALSE | 3:05 | |
| 4 | PTC tracking error | PTC, PTC3 | 80 | $3 \cdot 80 / 2 = 120$ | 1-count | <u>103</u> | TRUE | 3:40 (singleton) | |
| 5 | MKD Power switch degradation | SP2 | 60 | $3 \cdot 60 / 3 = 60$ | <u>P_D model</u> | 633 | n.a. ¹ | 2:20 | |
| 6 | MKD PTC card failure | PTC1-3 | 80 | $3 \cdot 80 / 1 = 240$ | - | 1140 | n.a. | 1:44 (singleton) | |
| 7 | MKB Power switch degradation | SW2 | 20 | $3 \cdot 20 / 6 = 10$ | <u>P_D model</u> | 633 | n.a. | 0:36 | |
| 8 | MKB HV power supply breakdown | PSH | 20 | $3 \cdot 20 / 1 = 60$ | - | 152 | TRUE | No data | |
| 9 | MKB HV power supply degradation | Not in the model | 20 | $3 \cdot 20 / 3 = 20$ | 1-count | 114 | TRUE | 1:18 | |
| 10 | MKD PTC power supply | PTC | 80 | $3 \cdot 80 / 1 = 240$ | - | <u>114</u> | TRUE | 2:03 (singleton) | |
| 11 | MKB Magnet sparking | Not in the model | 20 | $3 \cdot 20 / 1 = 60$ | - | - | n.a. | No data | |
| 12 | MKD Peltier cooling element | Not in the model | 30 | $3 \cdot 30 / 4 = 22.5$ | <u>Removed</u> | - | n.a. | No data | |

Advanced models for reliability prediction

► Goal → How to capture anomalies from observations

- ① Reliability growth models
- ② Interaction-dependency models (CCF)
- ③ Inaccurate diagnostics
- ④ Stress models
- ⑤ Failure on demand

Component Failure rates should always stay in the flat region



⑤
Failure on demand
Model apart

Tracking Availability

- ▶ **Narrow scope**
 - ▶ Faults that only manifest in operation → false beam dumps
- ▶ **Large scope**
 - ▶ Any fault that impacts (and retards) on the operation schedule
- ▶ **Systemic → balance safety and availability**
 - ▶ Is the system protected or overprotected?
 - ▶ Safety margins and safety policies
 - ▶ Trade-off and optimization

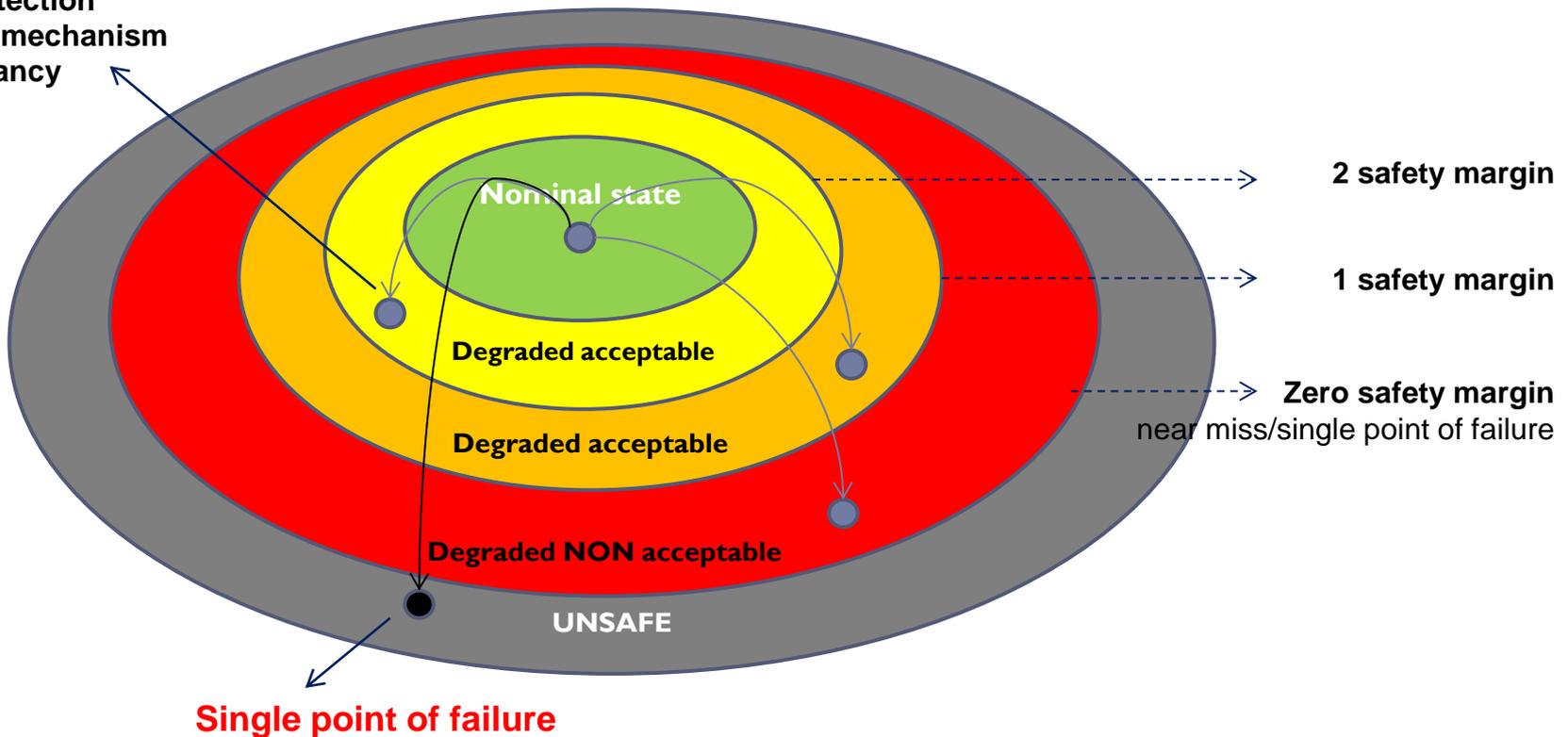
Safety margins

- ▶ **A state based approach** → safety by design guarantees that failures do not develop further and let the system operate at sufficient safety margins

1 - Fault detection

2 - Failsafe mechanism

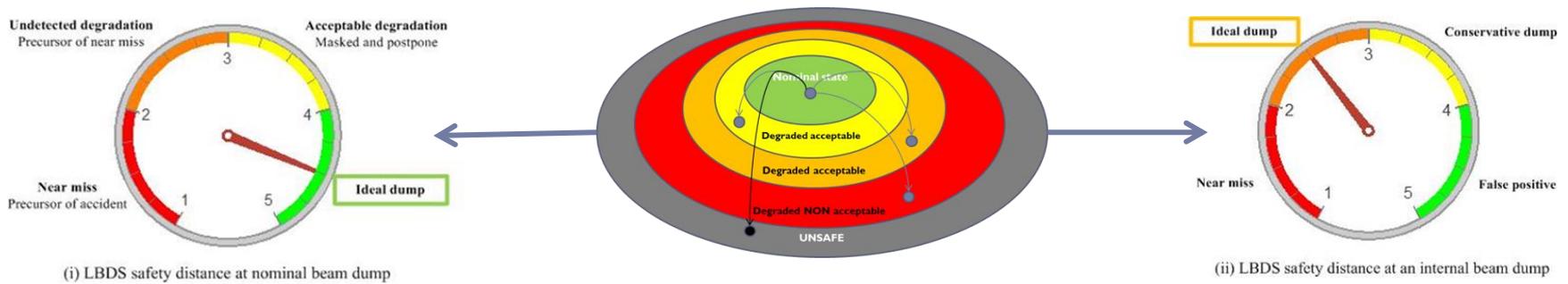
3 - Redundancy



The safety gauge

▶ Balance safety and availability

- ▶ Which ideal safety policy?
- ▶ Quantify the safety margins at every beam dump → black box model



Nominal beam dump

The system is fully available or in an acceptable degraded state

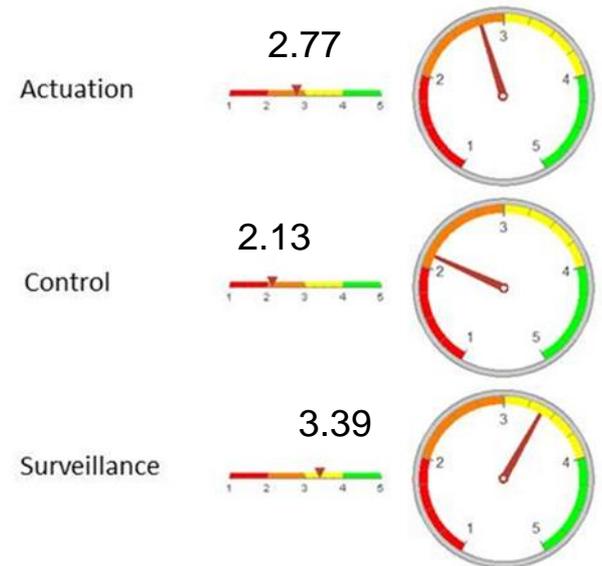
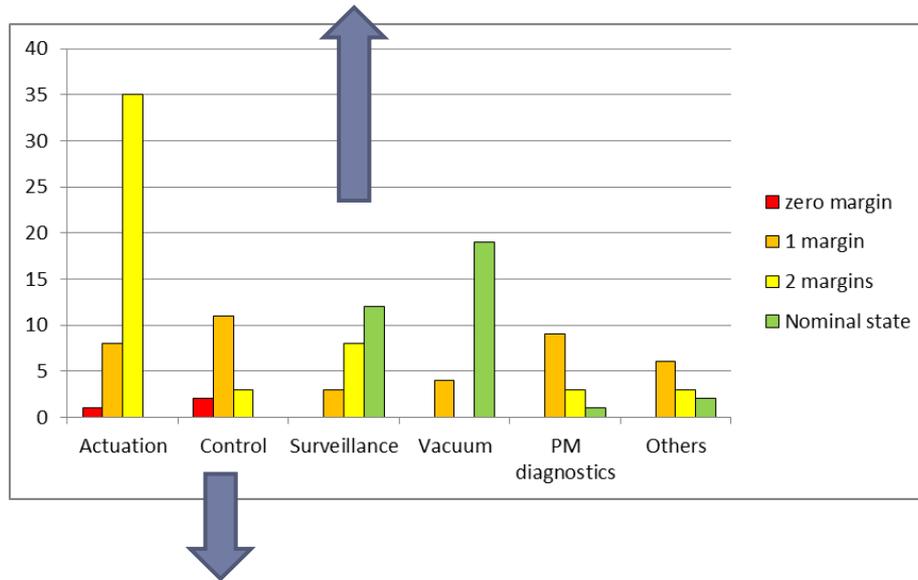
False beam dump

The internal dump must be justified → safety margin about to be eroded

Example: Safety margins for the LBDS

1. Every system was calculated a safety margin at the beam dump
2. The **average safety margin** was calculated over 2010-2012

Surveillance function is unbalanced against availability (over-protection)



Control function (TSDS) is the closest to the safety margins

Average safety margins at an internal beam dump

Design upgrades during LS1

Additional re-trigger from BIS
Upgrade of TSU cards
Distribution TSU over three crates

Electronics

Powering

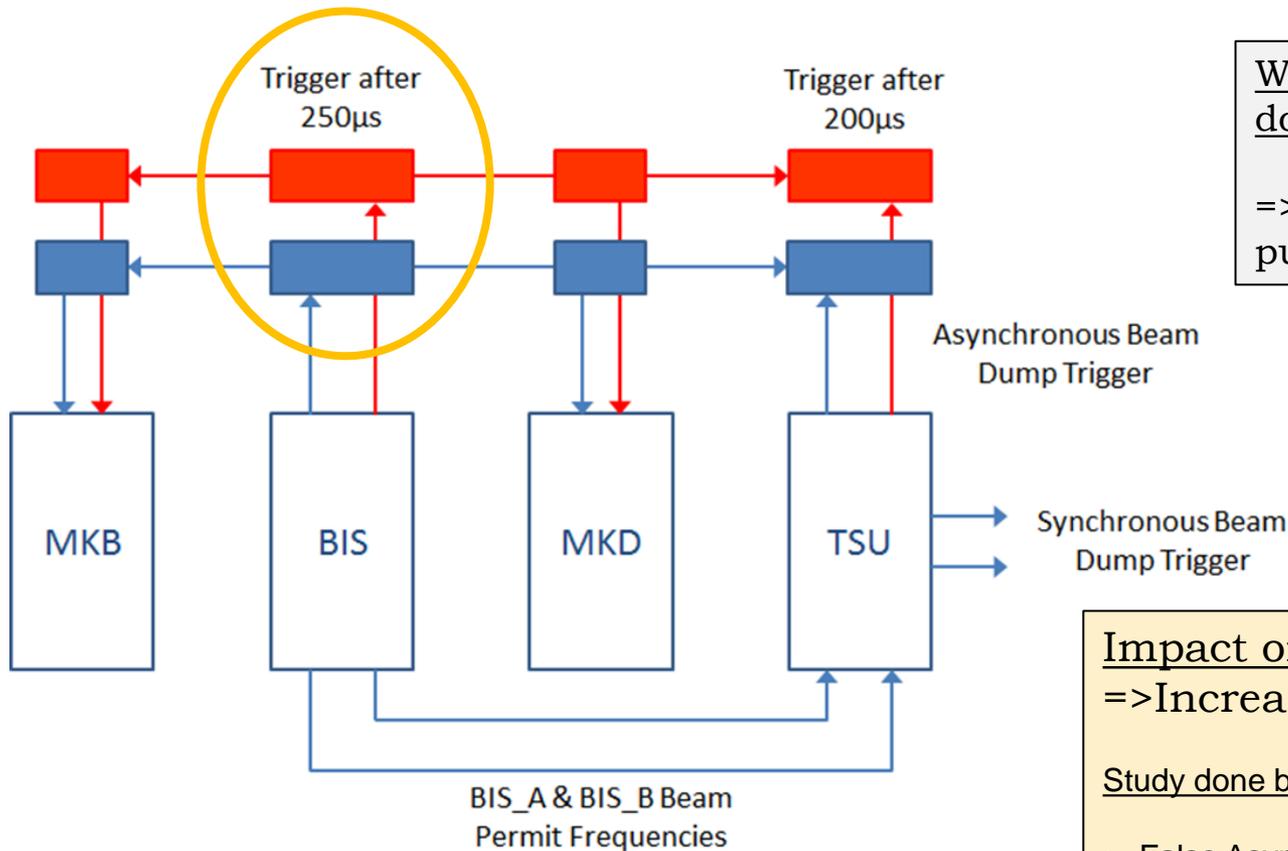
Changes to HV generators
Upgrade of PTUs
UPS configuration



Magnets

Add 2 MKB magnets per beam
Add shielding in MKD MKB cable ducts
MKB vacuum

Design update during LS1: Additional re-trigger from BIS



What happens if TSU cards do not send the triggers ?

=> BIS sends retrigger pulses after 250 us.

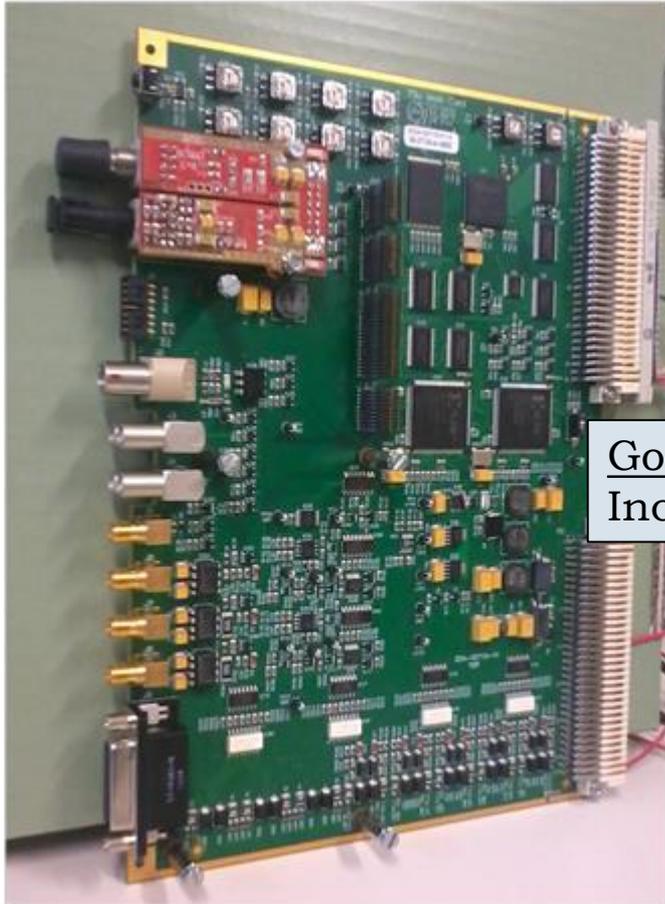
Goal:
Increase SAFETY

Impact on availability:
=> Increase of async dump rate ?

Study done by V.Vatansever:

- False Asynchronous beam dumps in 10 years:
⇒ Specified: **2** / Calculated: **0.025**
- False Synchronous beam dumps per year:
⇒ Specified: **2** / Calculated: **0.011**

Design update during LS1: Upgrade of TSU cards



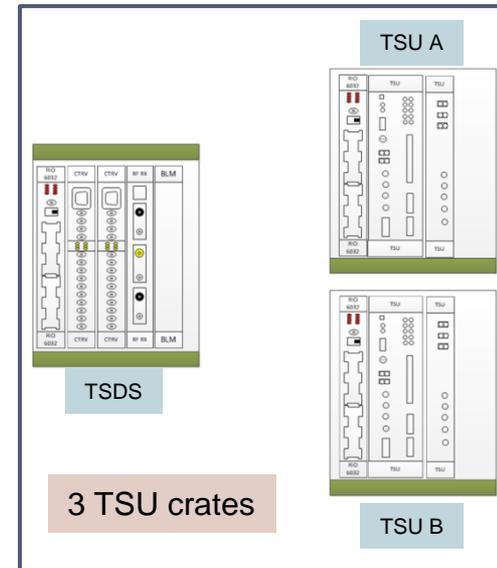
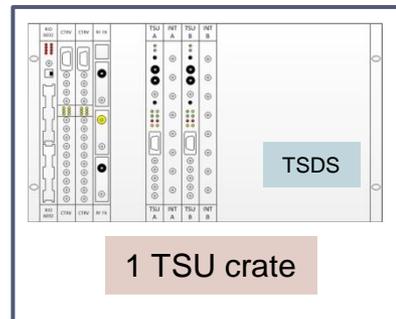
Goal:
Increase SAFETY

Motivation:

- External review of TSU v2 card (2010);
- CIBU power filter problems (2011);
- Internal review of LBDS Powering (2012);
- +12V problem in TSU VME crate (2012);
- Improvement of surveillance & diagnosis needed.

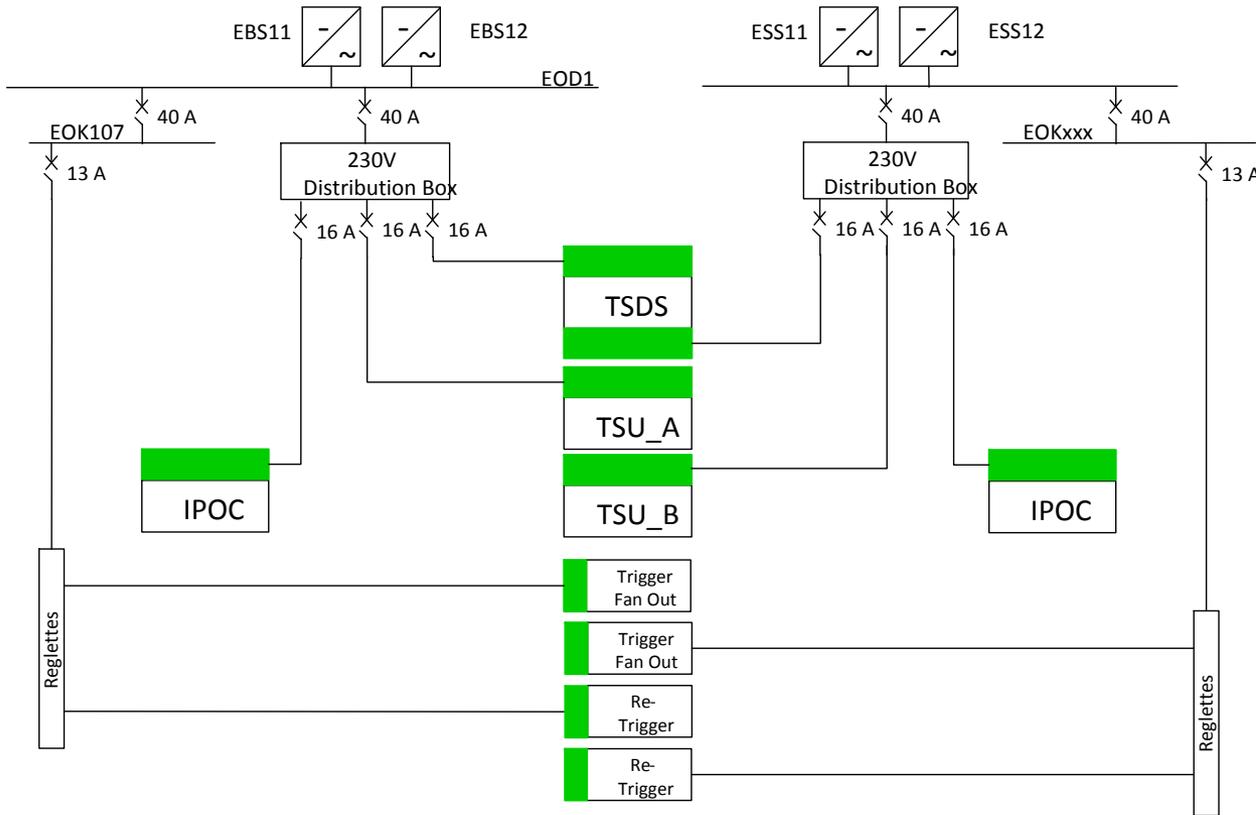
Implementation:

- Design of a new TSU card (v3)
- Deployment of the TSU cards over 3 separate crates



Impact on availability:
More surveillance systems => lower availability

Design update during LS1: LBDS powering modifications



- Add a separated connection to a second UPS (US65) for LBDS
- Individual circuit breaker for each crate PSU (Distribution Box)
- Software monitoring of all crate redundant PSU

Goal:
Increase SAFETY

Impact on availability:
More surveillance systems => lower availability

Design update during LS1: Add 2 MKB magnets (1 tank) per beam

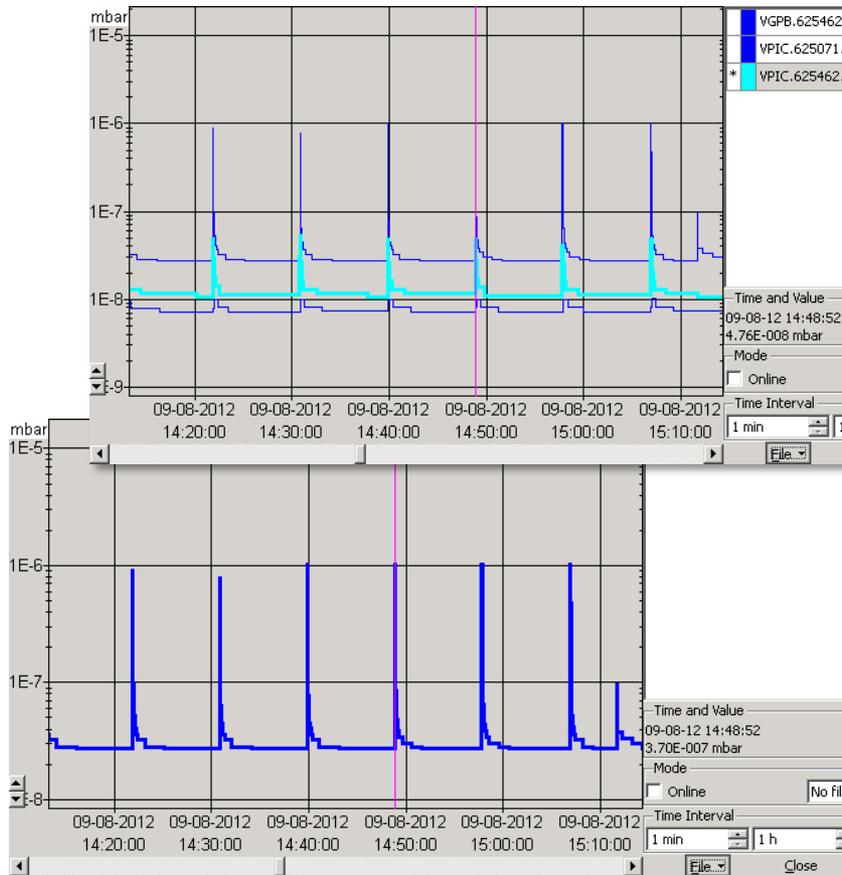
Goal:
Increase SAFETY

Impact on availability:

2 more MKBV (over 4 during LHC Run1):

- Increased risk of erratic triggering
- Increased risk of magnet flashover

Design update during LS1: MKB vacuum



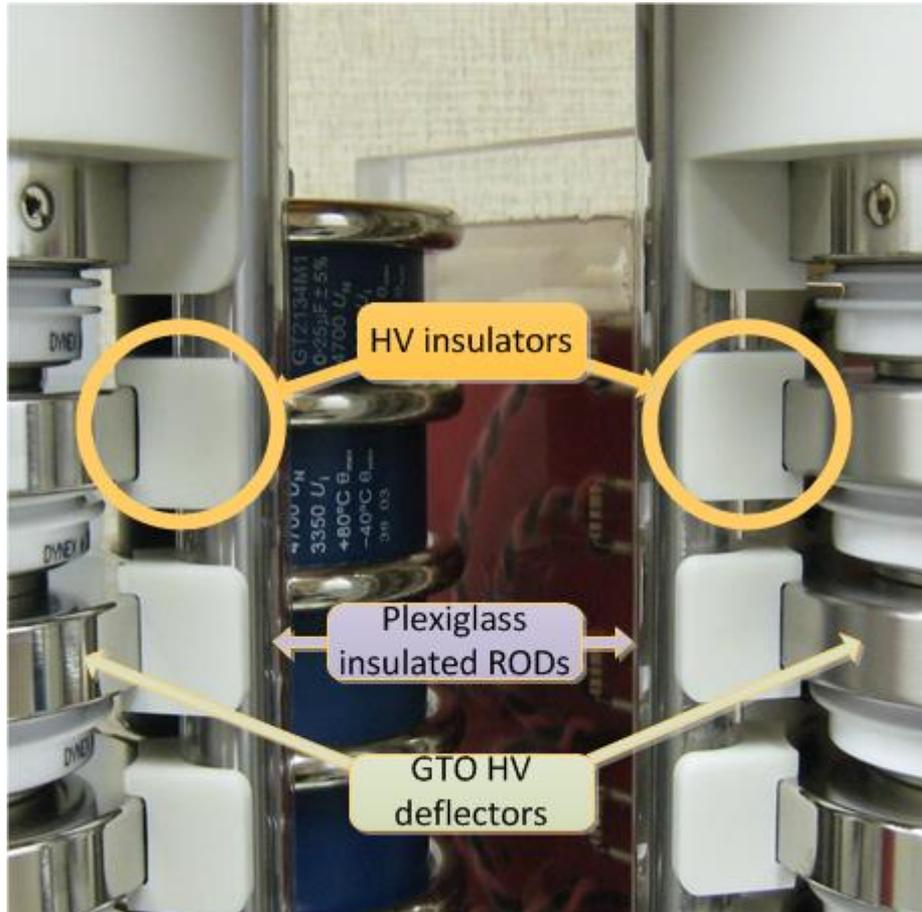
Courtesy of Fabien ANTONIOTTI

- Analogue signal very noisy
=> Masked since the beginning !
- Digital signal experienced glitches/spikes
=> Many dumps due to this problem !
(13 during LHC Run 1)
- 4 noisy vacuum probes masked in XPOC since the beginning

Problems identified by TE/VSC:
Intervention is planned.

Goal:
Increase AVAILABILITY

Design update during LS1: Changes to HV generators

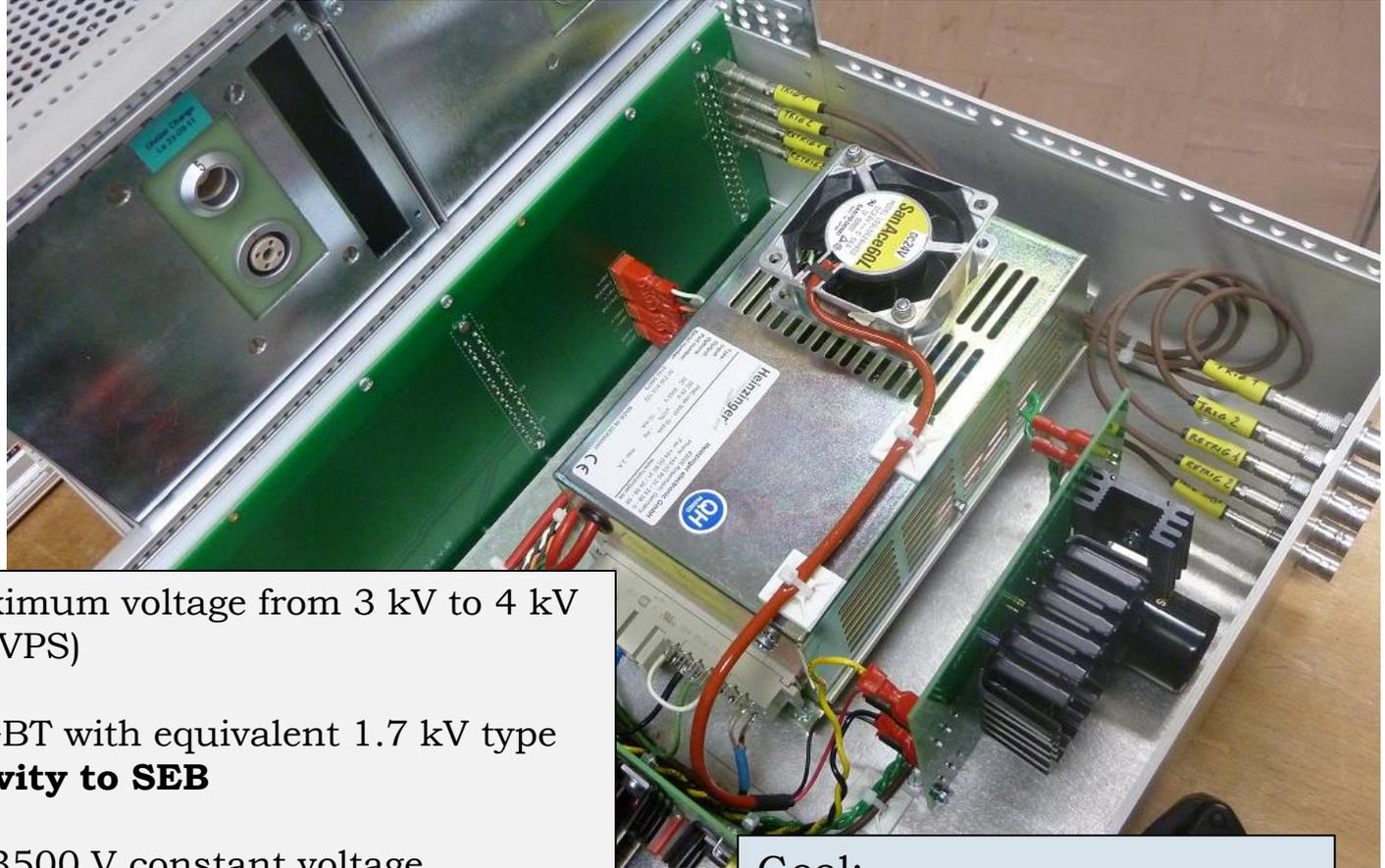


Sparking in the GTO stacks causing self-triggers: (operation limited to 5 TeV)

- => **HV insulators** are added between:
- Return current Plexiglas isolated rods;
 - GTO HV deflectors.

Goal:
Increase AVAILABILITY

Design update during LS1: Upgrade of PTUs



- Increase PTU maximum voltage from 3 kV to 4 kV (replacement of HVPS)
- Replace 1.2 kV IGBT with equivalent 1.7 kV type
=> **better sensitivity to SEB**
- Operate PTU at ~3500 V constant voltage
=> Increased GTO gate current
=> **less GTO wear out**

Goal:
Increase AVAILABILITY

Design update during LS1: Add shielding in MKD & MKB cable ducts



Add shielding in all MKD & MKB cable ducts
between UA and RA:

=> **less SEB problems**

Goal:
Increase AVAILABILITY

System analysis and recommendations (1)

- ▶ **Safety by design → implementation issues**
 - ▶ Prevent the generation of erratic triggers (MKD)
 - ▶ Loss of redundant chains and Common Cause of Failure (all)
 - ▶ Overlap between control functions and safety functions (TSDS)

- ▶ **Safety by design → functional, systemic issues**
 - ▶ Analysis of rare events (e.g. “Swiss cheese” models)
 - ▶ Safety measures as possible source of hazards
 - ▶ Functional dependencies and domino effects

- ▶ **Tools**
 - ▶ Safety standards
 - ▶ System analysis qualitative and probabilistic methods
 - ▶ Fault tracking → monitor that every components stays in the flat region and identify anomalies (aging? dependencies? stress?)

System analysis and recommendations (2)

- ▶ Scale up risks → operating at higher energies may demand tighter margins of safety and impact on availability

- 1. Review of the existing safety chains
 - ▶ Review SIL in the light of possible increased risks
- 2. New hazards or existing hazards that become safety relevant
 - ▶ New safety chains and interlocks after LS1 changes
 - ▶ New failsafe mechanisms as sources of false beam dumps

- ▶ Tools
 - ▶ Risk analysis
 - ▶ Real-time estimate of safety-availability balance → the safety gauge
... export the safety gauge (safety margin) concept to every system that has a non trivial safety-availability trade-off - it returns a metric easy to understand and that can be shared throughout designers and operators

Conclusions

- ▶ **Analysis of LBDS over 2010-2012 returned overall satisfying statistics**
 - ▶ Availability and safety improved along the operational period.
 - ▶ Anomalies sorted out.
 - ▶ Theoretical models in line with observations
- ▶ **Experience in methodologies is encompassing**
 - ▶ Hazards → system analysis → safety by design
 - ▶ Innovative methodologies → safety gauge
- ▶ **All design upgrades are safety-availability informed**
- ...

Conclusions (2): design upgrade during LS1

SAFETY is our main concern !

Most of important changes for **SAFETY improvement...**

...Perhaps **reducing AVAILIBILITY !**

Nonetheless, many changes are performed to **improve AVAILIBILITY...**

...where **SAFETY is not impacted.**

...question time



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Spare slides - recommendations

Sensitivity to unknowns

- ▶ Some failure modes were not foreseen in the theoretical model (7 over 26 recorded)
- ▶ Their impact is significant in the overall safety figures
 - ▶ They reduced the safety margin or impacted on availability

| <i>Function</i> | <i>With new failure modes</i> | <i>Without new failure mode</i> |
|-----------------|-------------------------------|---------------------------------|
| Actuation | 2.77 | 2.86 ↑ |
| Control | 2.13 | 2.58 ↑ |
| Surveillance | 3.39 | 2.85 ↓ |

R. Filippini, J. Uythoven Review of the LBDS safety and reliability analysis in the light of the operational experience 2010-2012, CERN-ATS-Note-2013-042 TECH. 2013

Recommendations (1)

- ▶ **Further investigations on failure mechanisms**
 - ▶ Common Cause Failure suspected in a few components such as the failure of three High Voltage power supplies in the MKD generators, two Triggering Units not responding, and the spurious firing of two Trigger Fan Out units. Further analysis on CCF and consequences on reliability is recommended.
- ▶ **Availability concerns**
 - ▶ 7 false beam dumps are from the vacuum
 - ▶ 12 failures from post mortem and diagnostics => cause of delays in re-arming
 - ▶ Diagnostics was not always accurate, faults fixed after several interventions
 - ▶ Some functions might be over-protected, e.g. LBDS surveillance
- ▶ **Safety concerns**
 - ▶ SIL3 is largely met for LBDS, SIL4 possible but further analysis is recommended
 - ▶ The control functions of the LBDS (TSDS) is estimated to have the smallest safety margin.
 - ▶ HW changes during LSI in TSDS (controls) and powering.

Recommendations (2)

▶ Data quality

- ▶ Good and large quantity, but inconsistencies existed as well as non-homogeneities in the data reporting, time stamps, consequences from diagnostics and intervention
- ▶ Improvements during the years should be consolidated by the definition of standard procedures of data reporting and tools for the automatic information retrieval

▶ Product assurance

- ▶ Several components did not meet the reliability specification because of design flaws, and were returned to the manufacturer (e.g. Asibus®, Power trigger power supply).

▶ Other issues

- ▶ Maintenance, and diagnostics had a relevant impact on operation
- ▶ A number of faults/errors are procedural (human factor) and should be taken into account for a more detailed analysis

Spare – Failure models



Control and surveillance functions (spare)

Not validated

| # | Failure mode | Model | Population | TTF (years) | | | | TTR (h:mm) |
|---|-------------------------------|------------------|------------------|-----------------|---------------------------------|------------|---------|---------------------|
| | | | | Raw | Corrected | Rel. pred. | H. test | |
| 1 | TSDS TSU spurious trigger | O, PL, S2, CLK | 4 | $3*4/3 = 4$ | 1-count 12 | 320 | n.a. | No data |
| 2 | SCSS voltage tab. corrupted | Not in the model | 2 | $3*2/1 = 6$ | - | - | n.a. | No data |
| 3 | BEM anybus error | TX1, TX2, TX3 | 50 | $3*50/5 = 30$ | 1-count 150 | 380 | TRUE | 0:37:00 |
| 4 | TSDS fan out spurious trigger | TO2 | 100 | $3*100/2 = 150$ | <u>β-model</u> | 16000 | n.a. | 1:20:00 (singleton) |
| 5 | TSDS TSU fail in both LBDS | C1, DR1, TO1 | 4 | $3*4/4 = 3$ | <u>β-model</u> | 157 | n.a. | 0:36 |
| 6 | SCSS PLC Dout board failure | Not in the model | 150 | $3*150/1 = 450$ | - | - | n.a. | 3:05 (singleton) |
| 7 | TSDS VME crate PS breakdown | Not in the model | 2 | $3*2/1 = 6$ | - | - | n.a. | No data |
| 8 | RTB out box, fail silent | OUT, DT1, C1 | 60 | $3*60/2 = 90$ | <u>P_D model</u> | 726 | n.a. | 0:26 (singleton) |
| 9 | RTB in box, VD fail silent | IN | 300 ¹ | $3*300/1 = 900$ | <u>Removed</u> | 162 | n.a. | No data |

| # | Failure mode | Model | Population | TTF (years) | | | | TTR (h:mm) |
|---|--------------------------------------|------------------|------------|-----------------|---------------------|------------|---------|-----------------------|
| | | | | Raw | Corrected | Rel. pred. | H. Test | |
| 1 | BEA power supply | Not in the model | 50 | $3*50/3 = 50$ | - | - | n.a. | 1:29:00 |
| 2 | Voltage divider | VD | 160 | $3*160/3 = 160$ | - | 1140 | n.a. | 0:37:00 (single data) |
| 3 | BEI energy tracking table | ER1, ER3 | 50 | $3*50/1 = 150$ | - | 386 | TRUE | 1:25:00 (single data) |
| 4 | BEA TX module stuck at timeout error | TX1 | 50 | $3*50/1 = 150$ | - | 786 | n.a. | No data |
| 5 | SCSS PLC Din board failure | Not in the model | 108 | $3*108/1 = 324$ | - | - | n.a. | 0:50:00 (single data) |
| 6 | SCSS PLC cabling failure | Not in the model | - | - | <u>Removed</u> | - | n.a. | No data |
| 7 | SCSS Asi Bus SEU | Not in the model | 4 | $3*4/10 = 1.2$ | 1-count <u>6</u> | - | n.a. | 3:07 |
| 8 | BEM anybus error | TX1, TX2, TX3 | 50 | $3*50/2 = 75$ | 1-count 150 | 380 | TRUE | 3:20 |

Failure on demand

- ▶ The failure model on demand assumes that the contribution to the failure is twofold:
 - ▶ Constant failure rate λ
 - ▶ Probability on demand P_D

Average failure rate
$$\frac{P_D N}{T} + \lambda = \frac{1}{TTF_{data}}$$

- ▶ **Example: MKD power switch**
 - ▶ 60 components, predicted (633) and calculated (60) TTF disagree, a probability on demand model is applied and results in $P_D = 3E-06$.
- ▶ Failure mode validated with corrected model

Failure Dependency

- ▶ The beta model assumes that the behavior at failure of similar components is not fully independent
 - ▶ The dependency is quantified by a beta factor (math. steps omitted)

$$TTF_{data} = (1 - \beta)TTF$$

- ▶ Example: MKD HV power supply breakdown
 - ▶ 30 components, predicted (150) and calculated (13) TTF disagree. A **Common Cause Failure** beta-model is introduced in addition to the constant failure rate => beta = 0.9 which is high.
- ▶ Failure mode validated but further investigation suggested

Hypothesis test

- ▶ The **hypothesis test** verifies that the assumption on the predicted TTF is true on the basis of the observations
 - ▶ The test consists of calculating the probability that the number of observed failures k_1 over a time T is compatible with the assumed distribution \Rightarrow the null-hypothesis H_0

$$P_0(k \geq k_1) = 1 - \sum_{k=0}^{k=k_1} p_0(k, T) = \begin{cases} > \alpha = 0.05 \Rightarrow H_0 \text{ is true} \\ \leq \alpha = 0.05 \Rightarrow H_0 \text{ is false} \end{cases}$$

- ▶ **Example: Power Trigger HV Power supply**
 - ▶ 60 components, predicted (9) and calculated (16) \Rightarrow TTF slightly disagree.
 - ▶ The hypothesis test is True.
- ▶ Failure mode validated after hypothesis test

Safety metrics

- ▶ The problem

- ▶ The evidence that all beams were safely dumped at every beam dump request for LBDS is a necessary but not sufficient condition to state that the system is SIL3 at least

- ▶ Rare events are hopefully not recordable but... their early development can be observed

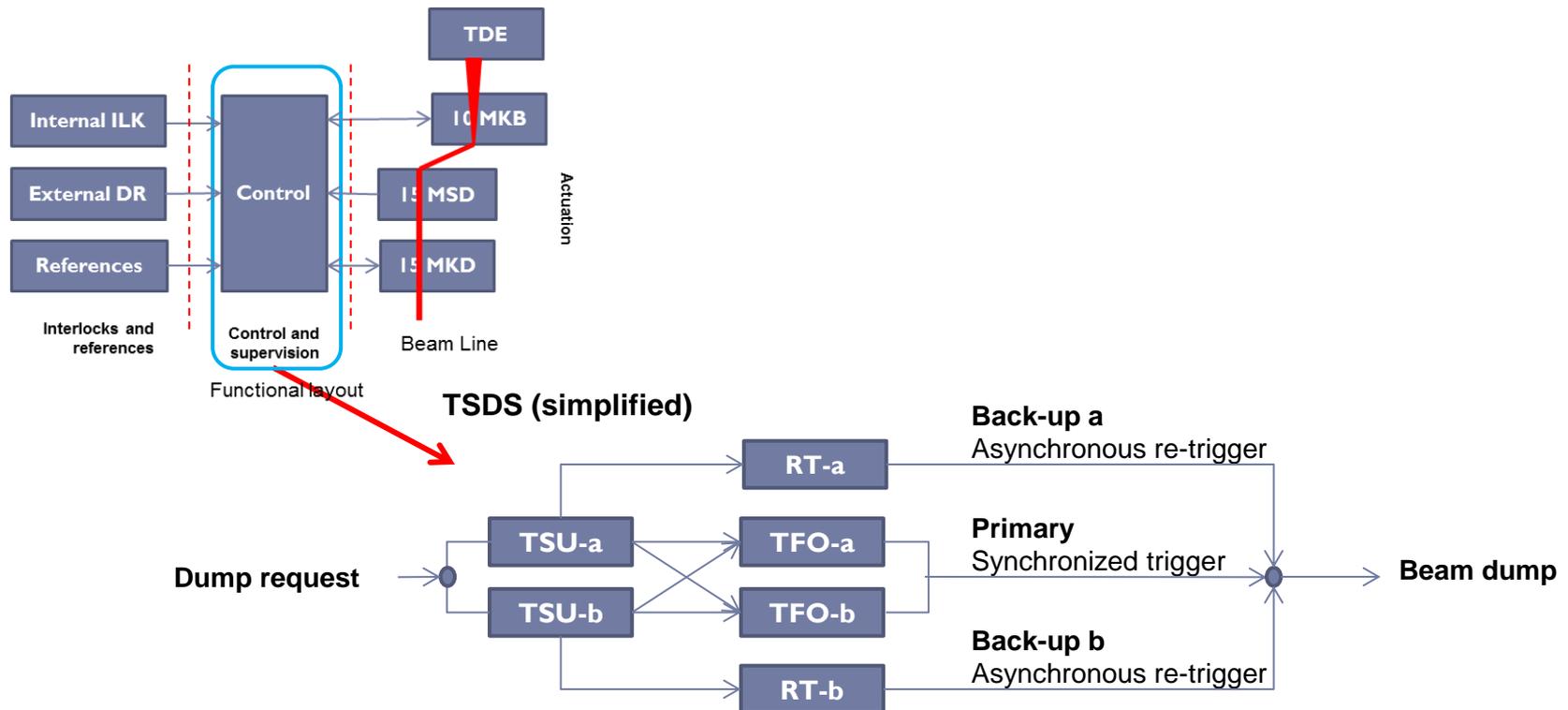
1. Look for near misses and close to near misses
2. Identify the event driven failure dynamics
3. **Set a metric for safety → safety margin**
4. Estimate SIL on the calculated safety margin

Spare - Safety



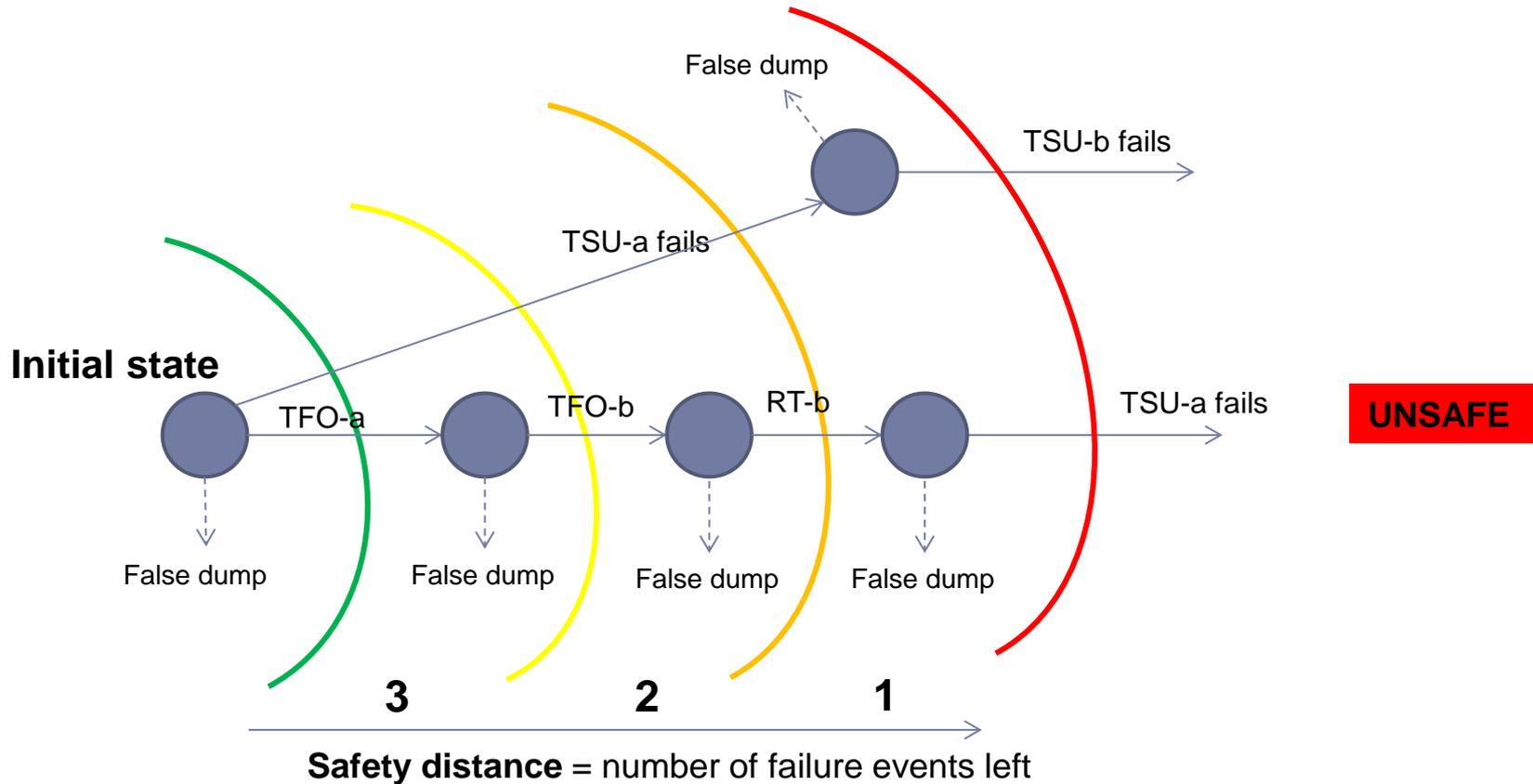
LBDS and safety by design

- ▶ The behavior at failure of the LBDS is conceived in order to ...
 - ▶ Tolerate faults by redundancy => fault masking
 - ▶ Prevent faults by surveillance => failsafe



Example: TSDS and safety distance

- ▶ Simplified state transition diagram of the TSDS
 - ▶ Some failure events may be detected and trigger a false dump



Actual safety (0)

▶ **Extreme outcomes and singularities**

- ▶ failure events that moved the LBDS to a potentially unsafe state, or close to it (near miss) before this was discovered.
- ▶ **1 erratic trigger of 2 MKDs over three years, from 30 independent TFO outputs**
 - ▶ The maximum failure rate threshold in order to be SIL3 at least is $7.2 \text{ E-}05/\text{h}$ which is met.
- ▶ **2 failure at zero safety margin (detected) in the actuation and control functions, in 3 years**
 - ▶ The maximum failure rate threshold for the control is $7.8 \text{ E-}05$. and the one for the actuation is $1.1 \text{ E-}03$, which are both SIL3 at least.

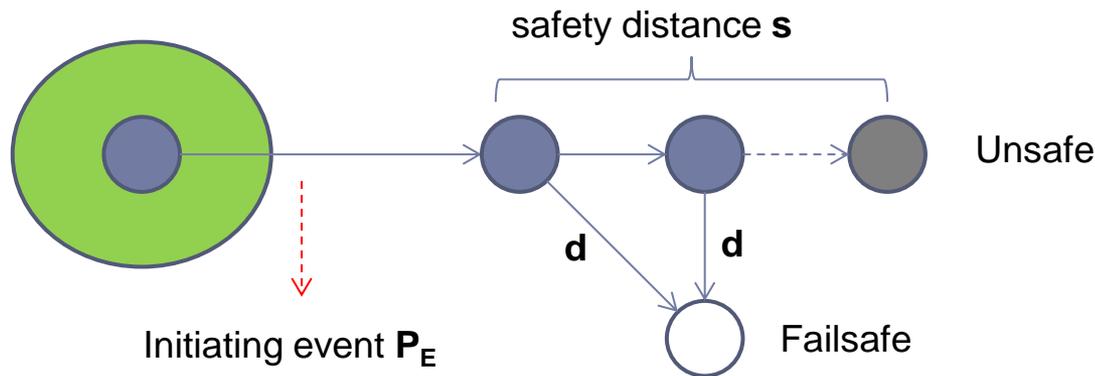
Actual safety (spare1)

▶ Problem statement

- ▶ Given the average safety distance at failures for each LBDS function, over the period 2010-2012, the objective is to calculate the maximum component failure rate below which LBDS is SIL3, for 300 days per year (total = 21600 h) with an average machine fill of 10 hours

▶ Data...

- ▶ P_E = probability of the initiating events (90/21600)
- ▶ $N = 1674$ number of components at failures in the LBDS
- ▶ s = safety distance
- ▶ d = detection rate; 0.73 for LBDS, 0.6 (actuation), 0.87 (control) 0.96(surveillance)



Actual safety (spare 2)

- ▶ The average failure process is approximated to a Poisson process, initiated by the initiating event E
- ▶ The system is safe if the probability of failure over one machine fill is SIL3 at least => the following **test** is a sufficient but not necessary condition for being SIL3

$$P = P_E [1 - F(d, N, \lambda, T, s)] < 1 - e^{-\lambda_{SIL3} T}$$

Continuous Poisson CDF

$\lambda_{SIL3} = 1 \times 10^{-7} / \text{h}$

Initiating event

residual safety margin

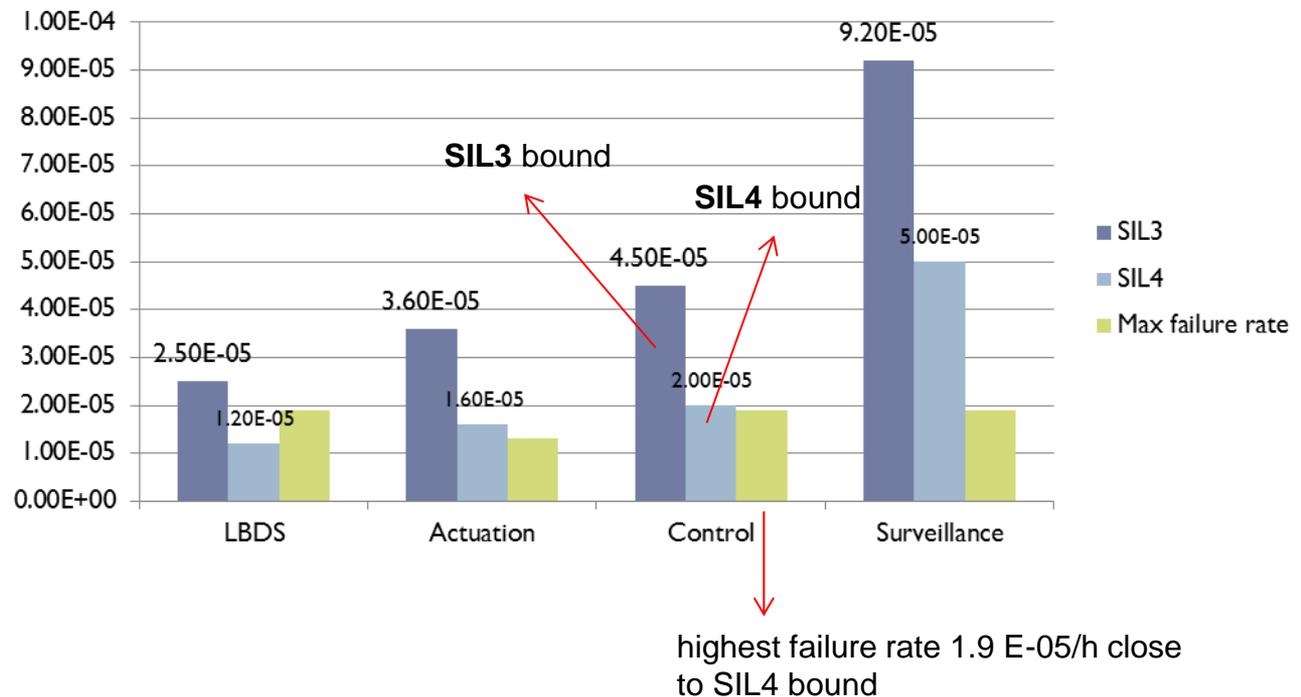
Probability of exceeding the safety margin s

SIL3 bounds

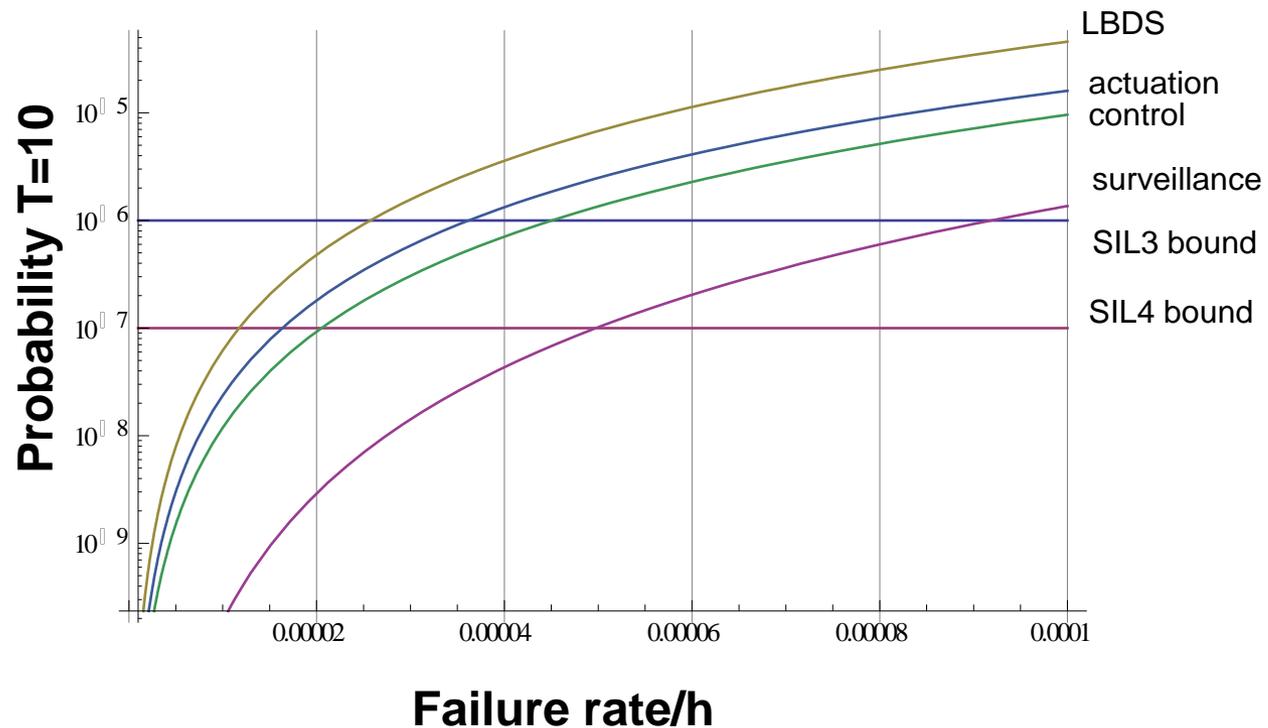
The failure rate threshold

Actual safety (3)

- ▶ Actuation, control, and surveillance functions **meet the safety requirements** individually and together as LBDS
 - ▶ Example: LBDS SIL3 bound is $2.5 \text{ E-}05/\text{h}$ - the highest rate is from the TSDSVME crate power supply failure = $1.9 \text{ E-}05/\text{h}$ with all other components being more reliable.



Safety: SIL3, SIL4 graphical tests



LBDS safety gauge 2010-2012

Table 1: Distribution of safety margins from operational failure data

| | Zero-margin | 1-margin | 2-margin | 3-margin | Safety distance | |
|----------------|-------------|-----------|-----------|-----------|----------------------|------------|
| | | | | | Average ¹ | Variance |
| Actuation | 1 | 8 | 35 | - | 2.77 | 0.23 |
| Control | - | 11 | 3 | - | 2.13 | 0.24 |
| Surveillance | - | 3 | 8 | 12 | 3.39 | 0.5 |
| LBDS | 2 | 22 | 46 | 12 | 2.82 | 0.5 |
| Vacuum | - | 4 | - | 19 | 3.65 | 0.57 |
| PM diagnostics | - | 9 | 3 | 1 | 2.38 | 0.39 |
| Others | - | 6 | 3 | 2 | 2.63 | 0.56 |



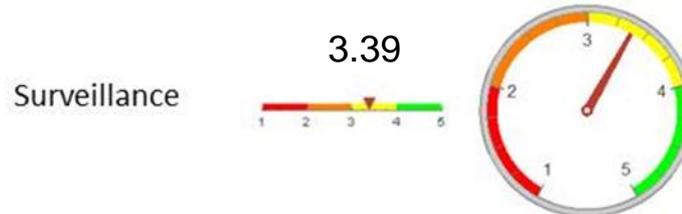
Ideal behaviour



Ideal behaviour



Poor safety margins



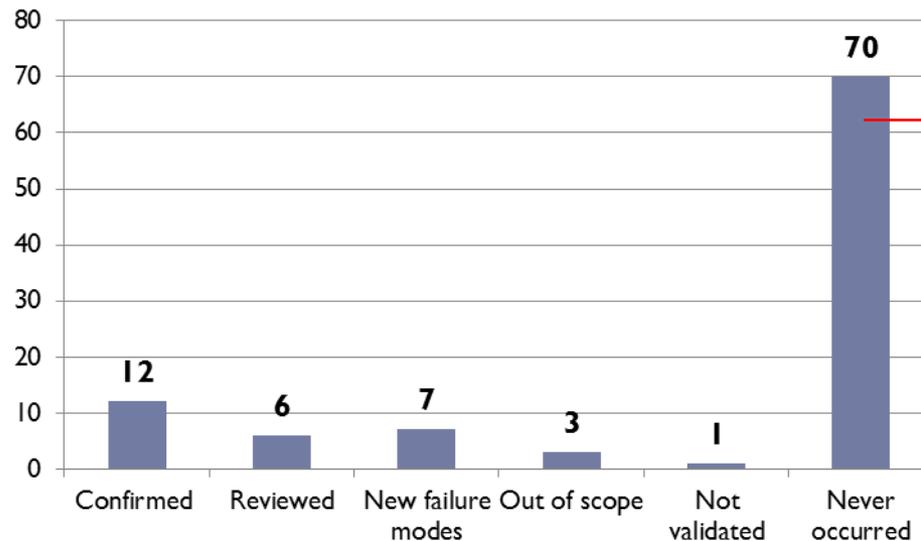
Over-protected at detriment of availability

Spare – various statistics



Failure modes

- ▶ 2518 LBDS components exposed to failures during 2010-2012 resulted in **90 failure events**, distributed in **29 different failure modes**...
- ▶ ...but almost 70 failure modes never occurred



Hypothesis test always true with the exception of the PTM power supply that was expected to fail

The most conservative TTF was taken

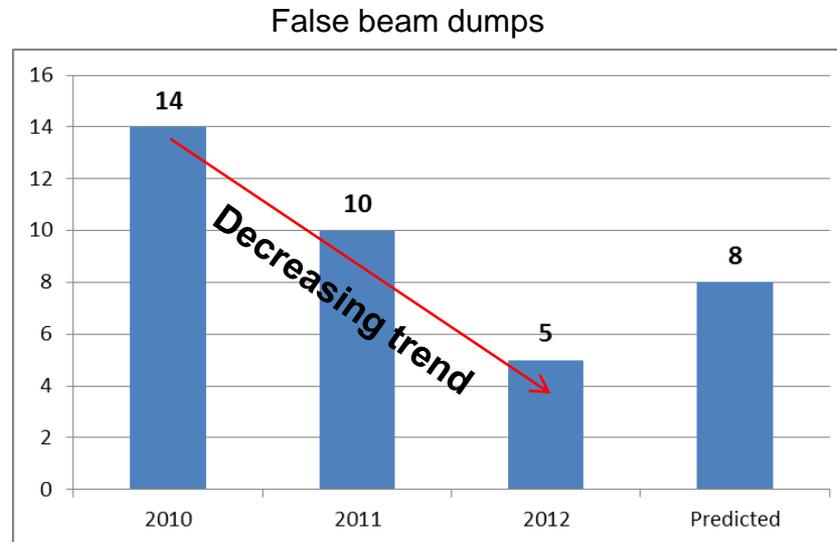
Actual availability

▶ Assumptions

- ▶ Only LBDS false beam dumps in the phases injection and stable beam are considered
- ▶ No repetition of the same internal dump request, i.e. occurrence of the same event (e.g. inaccurate diagnostics) after a short interval => 5 false dumps not considered.

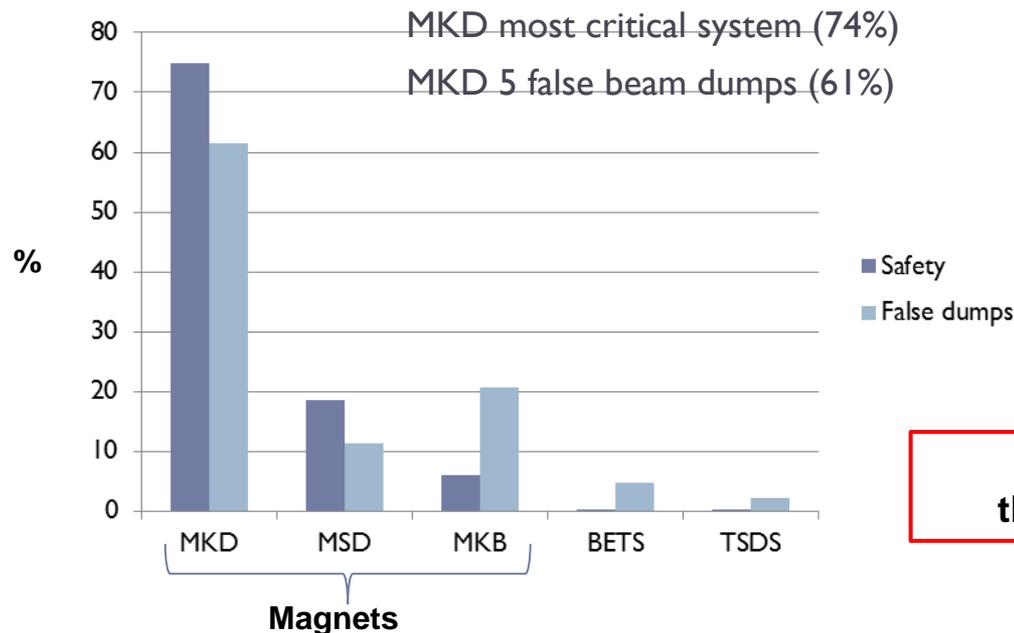
▶ Results

- ▶ The LBDS counted **29 false beam dumps**, against the 24 (on average) foreseen.
- ▶ Actuation (15) then surveillance (12) and control (2)



LBDS System analysis 2003-2006 (2)

- ▶ The probability of being not able to dump the beam on demand is estimated to be $1.8E-07$ per year of operation = largely **SIL4**
- ▶ The generated number of false beam dumps was **8 +/- 2**

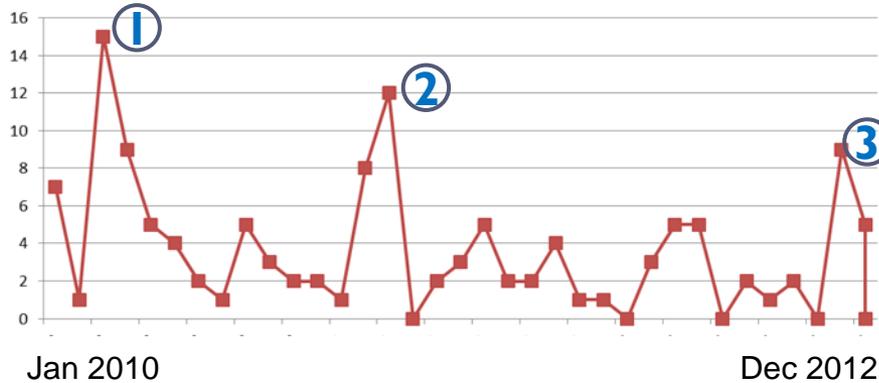


Predictions from
theoretical models!

Raw data by time series 2010-2012

Put together 8, 9 and 10

LBDS Failure events

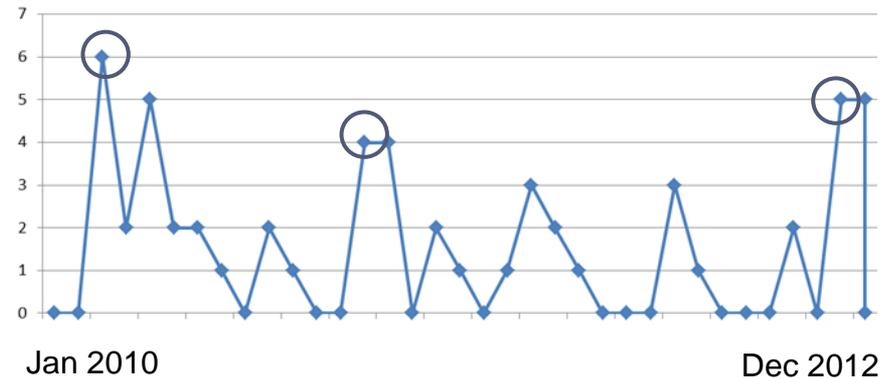


Anomalies

- 1 Vacuum and BEM Anybus®
- 2 Vacuum and diagnostics
- 3 SCSS Asibus®

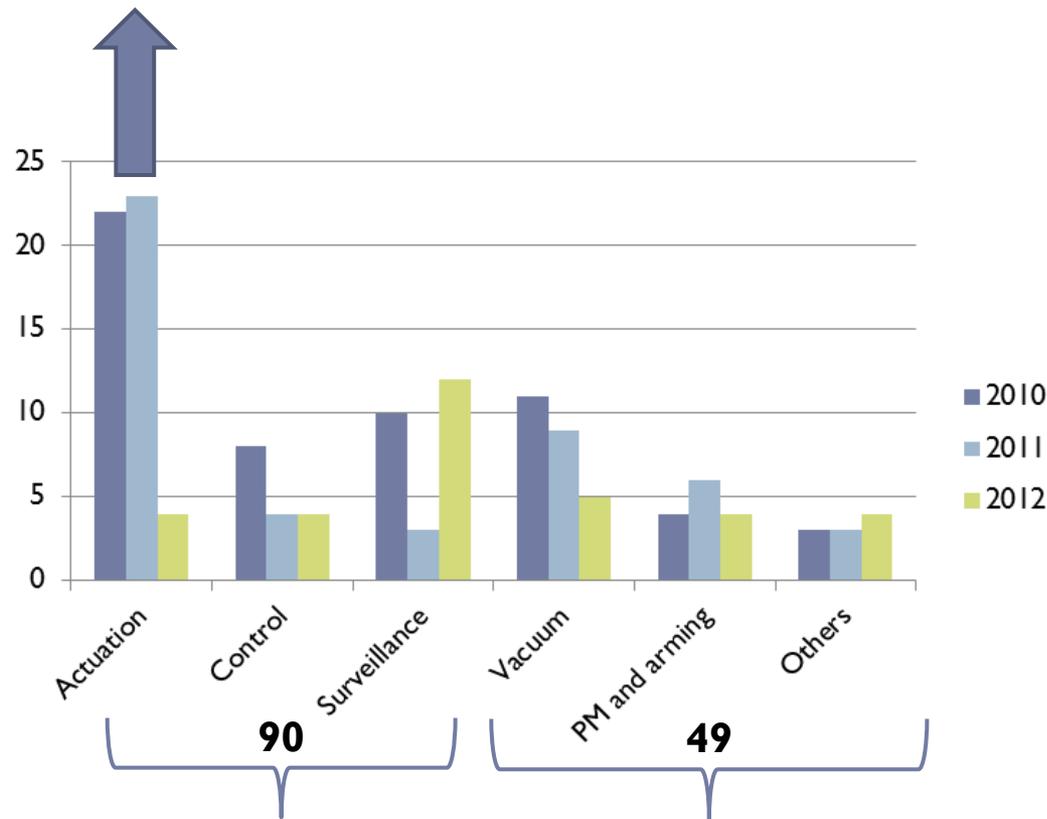
Statistics per month

LBDS false beam dumps



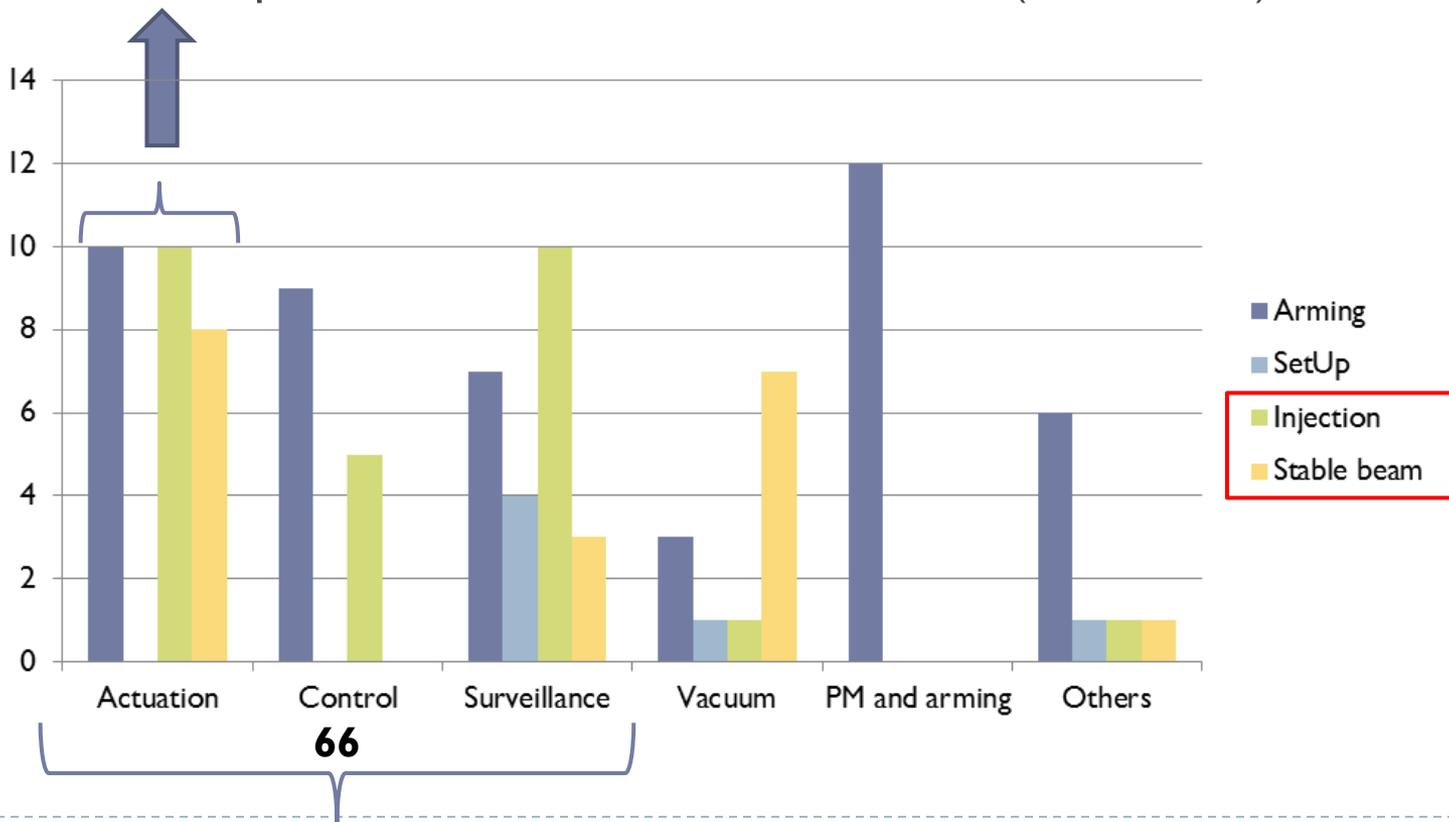
Failure distribution vs. functions

- ▶ 139 failure events recorded of which 90 in the LBDS
 - ▶ Actuation (MKD, MKB) is the largest contributor (60%)



LBDS false dumps vs. machine phase

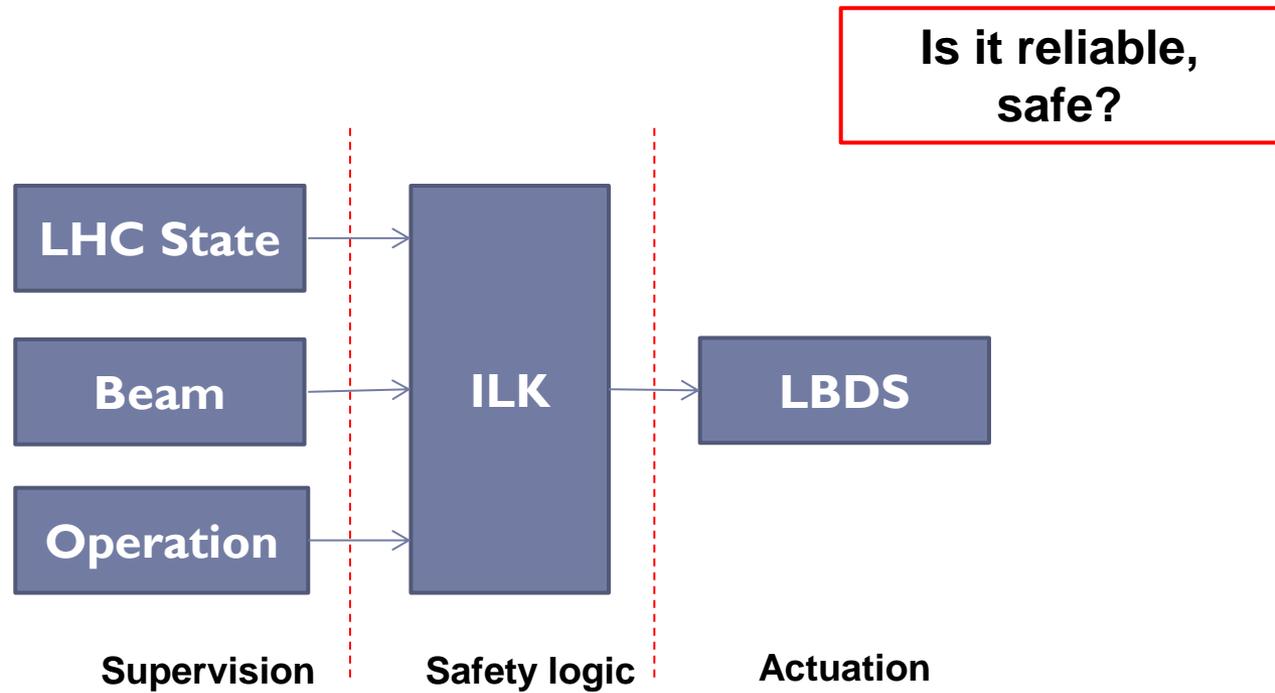
- ▶ A total of 97 events during 2010-2012 triggered a false dump (with or without the beam) of which 66 from the LBDS, i.e. 73% of the total
- ▶ The most important contributor is the actuation (MKD, MKB)



Spare - MPS

Machine Protection and LBDS

- ▶ The **LHC machine protection system** MPS allows operation with the beams only if the LHC is cleared from faults/errors, and it supervises its functioning in order to prevent that a failure may develop into a critical accident.



Machine Protection System 2003-2006

- ▶ The **reliability sub-working group** of the machine protection system working group was charged to perform the analysis of safety and availability of the most critical systems of the MPS
- ▶ The scope
 - ▶ All active devices, supervision and interlocking elements including the Beam Loss Monitors, Quench Protection System, Beam Interlocking Systems, Power Interlock System, LBDS.

Reliability w.g. 2006

| System | Unsafty/year | False dumps/year | |
|--------|---|--------------------|-----------|
| | | Average | Std. dev. |
| LBDS | $2.4 \times 10^{-7} \times 2 = 4.8 \times 10^{-7}$ | $4 \times 2 = 8.0$ | 2.0 |
| BIC | 1.4×10^{-8} | 0.5 | 0.5 |
| BLM | $\frac{1.44 \times 10^{-3}(\text{BLM1})}{0.06 \times 10^{-3}(\text{BLM2})}$ | 17.0 | 4.0 |
| | | | |
| PIC | 0.5×10^{-3} | 1.5 | 1.2 |
| QPS | 0.4×10^{-3} | 15.8 | 3.9 |
| MPS | 2.3×10^{-4} | 41.0 | 6.0 |

B. Todd, MP Workshop Annecy 2013

Most results confirmed, with a few exceptions

| | 2010 | 2011 | 2012 | Totals |
|---------------------------|------------|------------|------------|-------------|
| Qualifying Fills [#] | 355 | 503 | 585 | 1443 |
| MPS Equipment Failure [#] | 43 [12.7%] | 71 [14.1%] | 82 [14.0%] | 196 [13.6%] |
| Quench Protection | 24 | 48 | 56 | 128 |
| Beam Loss Monitors | 4 | 4 | 18 | 26 |
| Beam Dumping System | 9 | 11 | 4 | 24 |
| Software Interlock System | 4 | 2 | 4 | 10 |
| Powering Interlocks | - | 5 | - | 5 |
| Beam Interlock System | 2 | 1 | - | 3 |